



JUN 01 2004

JC185

PATENT &amp; TRADEMARK OFFICE

UNITED STATES PATENT AND TRADEMARK OFFICE

Page 1 of 2  
RECEIVED

MAY 17 2004

UNITED STATES DEPARTMENT OF COMMERCE  
United States Patent and Trademark Office  
Address: COMMISSIONER FOR PATENTS  
P.O. Box 1450  
Alexandria, Virginia 22313-1450  
[www.uspto.gov](http://www.uspto.gov)

OSHA &amp; MAY L.L.P.

APPL NO.	FILING OR 371 (c) DATE	ART UNIT	FIL FEE REC'D	ATTY.DOCKET NO	DRAWINGS	TOT CLMS	IND CLMS
10/779,904	02/17/2004	2133	770	02008.071003	38	3	3

22511  
OSHA & MAY L.L.P.  
1221 MCKINNEY STREET  
HOUSTON, TX 77010

## CONFIRMATION NO. 9608

## FILING RECEIPT



\*OC000000012596650\*

Date Mailed: 05/11/2004

Receipt is acknowledged of this regular Patent Application. It will be considered in its order and you will be notified as to the results of the examination. Be sure to provide the U.S. APPLICATION NUMBER, FILING DATE, NAME OF APPLICANT, and TITLE OF INVENTION when inquiring about this application. Fees transmitted by check or draft are subject to collection. Please verify the accuracy of the data presented on this receipt. If an error is noted on this Filing Receipt, please write to the Office of Initial Patent Examination's Filing Receipt Corrections, facsimile number 703-746-9195. Please provide a copy of this Filing Receipt with the changes noted thereon. If you received a "Notice to File Missing Parts" for this application, please submit any corrections to this Filing Receipt with your reply to the Notice. When the USPTO processes the reply to the Notice, the USPTO will generate another Filing Receipt incorporating the requested corrections (if appropriate).

## Applicant(s)

Masahiro Ishida, Tokyo, JAPAN;  
Takahiro Yamaguchi, Tokyo, JAPAN;  
Yoshihiro Hashimoto, Tokyo, JAPAN;

## Domestic Priority data as claimed by applicant

This application is a DIV of 09/980,891 12/03/2001  
which is a 371 of PCT/JP01/02910 04/04/2001

## Foreign Applications

04

JAPAN 2000-101867 04/06/2000

If Required, Foreign Filing License Granted: 05/11/2004

Projected Publication Date: 08/19/2004

Non-Publication Request: No

Early Publication Request: No

## Title

Method and apparatus for defect analysis of semiconductor integrated circuit

Action:	Reg. Correct SFR	Docketing
Base Date:	5-17-04	
Due Date:	6-17-04	
Deadline:	6-17-04	
Initials:	DK	
Atty/Sec. Initials:		

**Preliminary Class**

714

---

**LICENSE FOR FOREIGN FILING UNDER  
Title 35, United States Code, Section 184  
Title 37, Code of Federal Regulations, 5.11 & 5.15**

**GRANTED**

The applicant has been granted a license under 35 U.S.C. 184, if the phrase "IF REQUIRED, FOREIGN FILING LICENSE GRANTED" followed by a date appears on this form. Such licenses are issued in all applications where the conditions for issuance of a license have been met, regardless of whether or not a license may be required as set forth in 37 CFR 5.15. The scope and limitations of this license are set forth in 37 CFR 5.15(a) unless an earlier license has been issued under 37 CFR 5.15(b). The license is subject to revocation upon written notification. The date indicated is the effective date of the license, unless an earlier license of similar scope has been granted under 37 CFR 5.13 or 5.14.

This license is to be retained by the licensee and may be used at any time on or after the effective date thereof unless it is revoked. This license is automatically transferred to any related applications(s) filed under 37 CFR 1.53(d). This license is not retroactive.

The grant of a license does not in any way lessen the responsibility of a licensee for the security of the subject matter as imposed by any Government contract or the provisions of existing laws relating to espionage and the national security or the export of technical data. Licensees should apprise themselves of current regulations especially with respect to certain countries, of other agencies, particularly the Office of Defense Trade Controls, Department of State (with respect to Arms, Munitions and Implements of War (22 CFR 121-128)); the Office of Export Administration, Department of Commerce (15 CFR 370.10 (j)); the Office of Foreign Assets Control, Department of Treasury (31 CFR Parts 500+) and the Department of Energy.

**NOT GRANTED**

No license under 35 U.S.C. 184 has been granted at this time, if the phrase "IF REQUIRED, FOREIGN FILING LICENSE GRANTED" DOES NOT appear on this form. Applicant may still petition for a license under 37 CFR 5.12, if a license is desired before the expiration of 6 months from the filing date of the application. If 6 months has lapsed from the filing date of this application and the licensee has not received any indication of a secrecy order under 35 U.S.C. 181, the licensee may foreign file the application pursuant to 37 CFR 5.15(b).



JFW

PATENT  
ATTORNEY DOCKET NO. 02008/071003  
U.S. PATENT APPLICATION NO. 10/799,904

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Masahiro ISHIDA, *et al.*

Art Unit : 2133

Serial No. : 10/779,904

Examiner :

Filed : February 17, 2004

Title : METHOD AND APPARATUS FOR DEFECT ANALYSIS OF  
SEMICONDUCTOR INTEGRATED CIRCUIT

Commissioner of Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**REQUEST TO CORRECT FILING RECEIPT**

Applicants request that the filing date of the Japanese priority document be corrected from "04/06/2000" to --04/04/2000--.

Enclosed is a copy of the filing receipt as received from the PTO. The correct foreign priority information should be --Japanese Application No. 2000-101867, 04/04/2000--, as shown in the enclosed copy of the signed Declaration and Power of Attorney filed with this Divisional Patent Application on February 17, 2004.

Because this is a PTO error, no petition is believed necessary. However, if a petition is deemed to be required, please consider this paper as such and charge the appropriate fees to the Deposit Account 50-0591, reference No. 02008/071003.

PATENT  
ATTORNEY DOCKET NO. 02008/071003  
U.S. PATENT APPLICATION NO. 10/799,904

If there are any other charges, or any credits, please apply them to the same Deposit Account and reference No. 02008/071003.

Date: 5/27/04

Signature:

  
Jonathan P. Osha  
Reg. No. 33,986

OSHA & MAY L.L.P.  
1221 McKinney, Suite 2800  
Houston, Texas 77010

Telephone: 713/228-8600  
Facsimile: 713/228-8778

68271\_1

**CERTIFICATE OF MAILING BY FIRST CLASS MAIL (37 CFR 1.8)**Applicant(s): **Masahiro ISHIDA, et al.**

Docket No.

**02008/071003**Serial No.  
**10/779,904**Filing Date  
**February 17, 2004**

Examiner

Group Art Unit  
**2133**Invention: **METHOD AND APPARATUS FOR DEFECT ANALYSIS OF SEMICONDUCTOR INTEGRATED CIRCUIT**I hereby certify that this **Request to Correct Filing Receipt***(Identify type of correspondence)*

is being deposited with the United States Postal Service as first class mail in an envelope addressed to:

Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on

**May 27, 2004***(Date)***Charlotte L. Cunningham***(Typed or Printed Name of Person Mailing Correspondence)*

A handwritten signature in black ink that reads "Charlotte L. Cunningham".

*(Signature of Person Mailing Correspondence)*

Note: Each paper must have its own certificate of mailing.